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Application/Control No.	Applicant(s)/Patent under Reexamination
10/645,807	LIN ET AL.
Examiner	Art Unit
Tuan H. Nguyen	2618

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Class	Subclass	Date	Examiner
455	67.11,69	12/12/2007	T.N
455	452.2,522	12/12/2007.	T.N
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
All searches are on EAST data base.	12/12/2007	T.N		